

What is Claimed is:

1. A method for resolving timing violations introduced by a logic built-in self test (LBIST) sub-circuit formed within an underlying integrated circuit, said method comprising:

analyzing a circuit path-list corresponding to said integrated circuit for timing violations and generating a circuit timing violations analysis output;

generating a first LBIST/circuit path-list based on said circuit path-list and an LBIST path-list corresponding to said LBIST sub-circuit;

analyzing said first LBIST/circuit path-list for timing violations and generating an LBIST/circuit timing violations analysis output;

comparing said LBIST/circuit timing violations analysis output with said circuit timing violations analysis output;

generating an LBIST/circuit constraint file based on said comparing and predetermined protocols; and

generating a second LBIST/circuit path-list based on said circuit path-list, said LBIST path-list and said constraints file wherein said timing violations introduced by said LBIST sub-circuit are resolved in said second LBIST/circuit path-list.

2. A method in accordance with claim 1,

wherein said circuit path-list includes a set of paths wherein each path in said set corresponds to a different route traversing a predetermined sequence of circuit components in said integrated circuit.

3. A method in accordance with claim 2,

wherein said LBIST path-list includes a set of paths wherein each path in said set corresponds to a different route traversing a predetermined sequence of circuit components in said LBIST sub-circuit.

4. A method in accordance with claim 3, wherein said generating a first LBIST/circuit path-list further comprises:

generating a first scanned circuit path-list; and

inserting said LBIST path-list into said first scanned circuit path-list to generate said first LBIST/circuit path-list.

5. A method in accordance with claim 4, wherein said constraint file comprises of a set of said circuits in said LBIST path-list and a set of paths in said circuit path-list and wherein said generating a second LBIST/circuit path-list further comprises:

generating a second scanned circuit path-list;

modifying paths in said second scanned circuit path-list based on said paths in said constraint file; and

inserting said LBIST path-list into said second scanned circuit path-list based on said constraint file to generate said second LBIST/circuit path-list wherein said circuits in said constraint file are excluded from said inserting into said scanned circuit path-list and said generated second LBIST/circuit path-list.

6. A method in accordance with claim 5, wherein said predetermined sequence of circuit components comprising:

a first circuit component wherein said first circuit component is the first traversed component in said path; and

a second circuit component wherein said second circuit component is the last traversed component in said path.

7. A method in accordance with claim 6, wherein said first traversed component is a scan-enabled electronic flip-flop.

8. A method in accordance with claim 6, wherein said first traversed component is a memory output port.

9. A method in accordance with claim 6, wherein said first traversed component is an external input port.

10. A method in accordance with claim 6, wherein said last traversed component is a scan-enabled electronic flip-flop.

11. A method in accordance with claim 6, wherein said last traversed component is a memory input port.

12. A method in accordance with claim 6, wherein said last traversed component is an external output port.

13. A method in accordance with claim 6,  
wherein said analyzing said circuit path-list includes performing a functional mode timing violations analysis of said circuit path-list; and,  
wherein said generating a circuit timing violation analysis output includes generating a circuit functional mode timing violations output path-list.

14. A method in accordance with claim 13, wherein said analyzing said first LBIST/circuit path-list further comprises:

analyzing said first LBIST/circuit path-list for functional mode timing violations and generating an LBIST/circuit functional mode timing violations output path-list; and

analyzing said first LBIST/circuit path-list for an LBIST mode timing violations and generating an LBIST/circuit LBIST mode timing violations output path-list,

wherein said generated LBIST/circuit timing violations analysis output includes said functional mode timing violations output path-list and said LBIST mode timing violations output path-list.

15. A method in accordance with claim 14, wherein said comparing further comprises:

comparing said LBIST/circuit functional mode timing violations output path-list with said circuit timing violations analysis output path-list and generating a first comparison output path-list; and

identifying in said first comparison output path-list a path with a circuit component causing timing violation, wherein said identifying is performed based on said predetermined identification protocols.

16. A method in accordance with claim 14, wherein said comparing further comprises: comparing said LBIST/circuit LBIST mode timing violations output path-list with said LBIST/circuit functional mode timing violations output path-list and generating a second comparison output path-list; and

identifying in said second comparison output path-list a path with a timing violation.

17. A method in accordance with claim 15, wherein said comparing further comprises: separating each path in said LBIST/circuit functional mode timing violations output path-list exclusive from said circuit timing violations analysis output path-list wherein said first comparison output includes said separated paths.

18. A method in accordance with claim 17, wherein said timing violation is a control point timing violation caused by a control point circuit.

19. A method in accordance with claim 17, wherein said timing violation is an observe point timing violation caused by an observe point circuit.

20. A method in accordance with claim 17, wherein said timing violation is an x-bounding timing violation caused by an x-bounding circuit.

21. A method in accordance with claim 18, said predetermined identification protocols comprising:

comparing each path in said separated paths in said first comparison output path-list with a predetermined control-point-insertion database to identify said control-point timing violation circuits in said path,

wherein said constraint file includes said identified control-point timing violation circuits in said path.

22. A method in accordance with claim 19, said predetermined identification protocols comprising:

comparing each path in said separated paths in said first comparison output path-list with a predetermined observe-point-insertion database to identify said observe-point timing violation circuits in said path,

wherein said constraint file includes said identified observe-point timing violation circuits in said path.

23. A method in accordance with claim 20, said predetermined identification protocols comprising:

comparing each path in said separated paths in said first comparison output path-list with a predetermined x-bounding-insertion database to identify said x-bounding timing violation circuits in said path,

wherein said constraint file includes said identified x-bounding timing violation circuits in said path.

24. A method in accordance with claim 16, wherein said comparing further comprises:

separating each path in said LBIST/circuit LBIST mode timing violations output path-list exclusive from said LBIST/circuit functional mode timing violations output path-list wherein said constraints file includes said separated paths.

25. A method in accordance with claim 24, wherein said timing violation is a multi-cycle-path violation.

26. A method in accordance with claim 24, wherein said timing violation is a false-path violation.

27. A method in accordance with claim 23, wherein said modifying comprising:

suppressing a capture of said last traversed scan-enabled electronic flip-flop in each said path.

28. A method in accordance with claim 23, further comprising:

determining each path in said first LBIST/circuit path-list whose first traversed circuit component is a first circuit component in said predetermined sequence of circuit components in each said separated path; and

suppressing a capture of a last traversed scan-enabled electronic flip-flop in each of said determined paths.

29. A method in accordance with claim 24, further comprising:

suppressing a capture of a last traversed scan-enabled electronic flip-flop in said separated paths.

30. A method in accordance with claim 29, wherein said suppressed component is a receiving flip-flop.

31. A system for resolving timing violations introduced by a logic built-in self test (LBIST) sub-circuit formed within an underlying integrated circuit, said system comprising:

means for analyzing a circuit path-list corresponding to said integrated circuit for timing violations and generating a circuit timing violations analysis output;

means for generating a first LBIST/circuit path-list based on said circuit path-list and an LBIST path-list corresponding to said LBIST sub-circuit;

means for analyzing said first LBIST/circuit path-list for timing violations and generating an LBIST/circuit timing violations analysis output;

means for comparing said LBIST/circuit timing violations analysis output with said circuit timing violations analysis output;

means for generating an LBIST/circuit constraint file based on said comparing and predetermined protocols; and

means for generating a second LBIST/circuit path-list based on said circuit path-list, said LBIST path-list and said constraints file wherein said timing violations introduced by said LBIST sub-circuit are resolved in said second LBIST/circuit path-list.

32. A system in accordance with claim 31,  
wherein said circuit path-list includes a set of paths wherein each path in said set corresponds to a different route traversing a predetermined sequence of circuit components in said integrated circuit.

33. A system in accordance with claim 32,  
wherein said LBIST path-list includes a set of paths wherein each path in said set corresponds to a different route traversing a predetermined sequence of circuit components in said LBIST sub-circuit.

34. A system in accordance with claim 33, wherein said means for generating a first LBIST/circuit path-list further comprises:

means for generating a first scanned circuit path-list; and

means for inserting said LBIST path-list into said first scanned circuit path-list to generate said first LBIST/circuit path-list.

35. A system in accordance with claim 34, wherein said constraint file comprises of a set of said circuits in said LBIST path-list and a set of paths in said circuit path-list and wherein said means for generating a second LBIST/circuit path-list further comprises:

means for generating a second scanned circuit path-list;

means for modifying paths in said second scanned circuit path-list based on said paths in said constraint file; and

means for inserting said LBIST path-list into said second scanned circuit path-list based on said constraint file to generate said second LBIST/circuit path-list wherein said circuits in said constraint file are excluded from said inserting into said scanned circuit path-list and said generated second LBIST/circuit path-list.

36. A system in accordance with claim 35, wherein said predetermined sequence of circuit components comprising:

a first circuit component wherein said first circuit component is the first traversed component in said path; and

a second circuit component wherein said second circuit component is the last traversed component in said path.

37. A system in accordance with claim 36, wherein said first traversed component is a scan-enabled electronic flip-flop.

38. A system in accordance with claim 36, wherein said first traversed component is a memory output port.

39. A system in accordance with claim 36, wherein said first traversed component is an external input port.

40. A system in accordance with claim 36, wherein said last traversed component is a scan-enabled electronic flip-flop.

41. A system in accordance with claim 36, wherein said last traversed component is a memory input port.

42. A system in accordance with claim 36, wherein said last traversed component is an external output port.

43. A system in accordance with claim 36,  
wherein said means for analyzing said circuit path-list includes means for performing a functional mode timing violations analysis of said circuit path-list; and,  
wherein said means for generating a circuit timing violation analysis output includes means for generating a circuit functional mode timing violations output path-list.

44. A system in accordance with claim 43, wherein said means for analyzing said first LBIST/circuit path-list further comprises:

means for analyzing said first LBIST/circuit path-list for functional mode timing violations and generating an LBIST/circuit functional mode timing violations output path-list; and

means for analyzing said first LBIST/circuit path-list for an LBIST mode timing violations and generating an LBIST/circuit LBIST mode timing violations output path-list,

wherein said generated LBIST/circuit timing violations analysis output includes said functional mode timing violations output path-list and said LBIST mode timing violations output path-list.

45. A system in accordance with claim 44, wherein said means for comparing further comprises:

means for comparing said LBIST/circuit functional mode timing violations output path-list with said circuit timing violations analysis output path-list and generating a first comparison output path-list; and

means for identifying in said first comparison output path-list a path with a circuit component causing timing violation, wherein said identifying is performed based on said predetermined identification protocols.

46. A system in accordance with claim 44, wherein said means for comparing further comprises:

means for comparing said LBIST/circuit LBIST mode timing violations output path-list with said LBIST/circuit functional mode timing violations output path-list and generating a second comparison output path-list; and

means for identifying in said second comparison output path-list a path with a timing violation.

47. A system in accordance with claim 45, wherein said means for comparing further comprises:

means for separating each path in said LBIST/circuit functional mode timing violations output path-list exclusive from said circuit timing violations analysis output path-list wherein said first comparison output includes said separated paths.

48. A system in accordance with claim 47, wherein said timing violation is a control point timing violation caused by a control point circuit.

49. A system in accordance with claim 47, wherein said timing violation is an observe point timing violation caused by an observe point circuit.

50. A system in accordance with claim 47, wherein said timing violation is an x-bounding timing violation caused by an x-bounding circuit.

51. A system in accordance with claim 48, said predetermined identification protocols comprising:

a protocol for comparing each path in said separated paths in said first comparison output path-list with a predetermined control-point-insertion database to identify said control-point timing violation circuits in said path,

wherein said constraint file includes said identified control-point timing violation circuits in said path.

52. A system in accordance with claim 49, said predetermined identification protocols comprising:

a protocol for comparing each path in said separated paths in said first comparison output path-list with a predetermined observe-point-insertion database to identify said observe-point timing violation circuits in said path,

wherein said constraint file includes said identified observe-point timing violation circuits in said path.

53. A system in accordance with claim 50, said predetermined identification protocols comprising:

a protocol for comparing each path in said separated paths in said first comparison output path-list with a predetermined x-bounding-insertion database to identify said x-bounding timing violation circuits in said path,

wherein said constraint file includes said identified x-bounding timing violation circuits in said path.

54. A system in accordance with claim 46, wherein said means for comparing further comprises:

means for separating each path in said LBIST/circuit LBIST mode timing violations output path-list exclusive from said LBIST/circuit functional mode timing violations output path-list wherein said constraints file includes said separated paths.

55. A system in accordance with claim 54, wherein said timing violation is a multi-cycle-path violation.

56. A system in accordance with claim 54, wherein said timing violation is a false-path violation.

57. A system in accordance with claim 53, wherein said means for modifying comprising: means for suppressing a capture of said last traversed scan-enabled electronic flip-flop in each said path.

58. A system in accordance with claim 53, further comprising:

means for determining each path in said first LBIST/circuit path-list whose first traversed circuit component is a first circuit component in said predetermined sequence of circuit components in each said separated path; and

means for suppressing a capture of a last traversed scan-enabled electronic flip-flop in each of said determined paths.

59. A system in accordance with claim 54, further comprising:

means for suppressing a capture of a last traversed scan-enabled electronic flip-flop in said separated paths.

60. A system in accordance with claim 59, wherein said suppressed component is a receiving flip-flop.

61. A system for resolving timing violations introduced by a logic built-in self test (LBIST) sub-circuit formed within an underlying integrated circuit, said system comprising:

a first analyzer subsystem adapted to receive and analyze a circuit path-list corresponding to said integrated circuit for timing violations and generate a circuit timing violations analysis output;

a first path-list generator subsystem in operative electrical communication with said first analyzer subsystem and adapted to generate a first LBIST/circuit path-list based on said circuit path-list and an LBIST path-list corresponding to said LBIST sub-circuit;

an second analyzer subsystem in operative electrical communication with said first path-list generator subsystem and adapted to receive and analyze said first LBIST/circuit path-list for timing violations and generating an LBIST/circuit timing violations analysis output;

a comparator subsystem in operative electrical communication with said second analyzer subsystem and said first analyzer subsystem, and adapted to receive and to compare said LBIST/circuit timing violations analysis output with said circuit timing violations analysis output, and to output a comparison result;

a second path-list generator subsystem in operative electrical communication with said comparator subsystem and adapted to generate an LBIST/circuit constraint file based on said comparison output and predetermined protocols; and

a third path-list generator subsystem in operative electrical communication with said second path-list generator subsystem and adapted to generate a second LBIST/circuit path-list based on said circuit path-list, said LBIST path-list, and said constraints file wherein said timing violations introduced by said LBIST sub-circuit are resolved in said second LBIST/circuit path-list.

62. A system in accordance with claim 61,

wherein said circuit path-list includes a set of paths wherein each path in said set corresponds to a different route traversing a predetermined sequence of circuit components in said integrated circuit.

63. A system in accordance with claim 61,

wherein said LBIST circuit path-list includes a set of paths wherein each path in said set corresponds to a different route traversing a predetermined sequence of circuit components in said LBIST sub-circuit.

64. A system in accordance with claim 63, wherein said first path-list generator subsystem further comprises:

a fourth generator subsystem adapted to generate a first scanned circuit path-list; and

a first insertion subsystem adapted to insert said LBIST path-list into said first scanned circuit path-list to generate said first LBIST/circuit path-list.

65. A system in accordance with claim 64, wherein said constraint file comprises of a set of said circuits in said LBIST path-list and a set of paths in said circuit path-list and wherein said third path-list generator subsystem further comprises:

a fifth generator subsystem adapted to generate a second scanned circuit path-list;

a modifier subsystem adapted to modify paths in said second scanned circuit path-list based on said paths in said constraint file; and

a second insertion subsystem adapted to insert said LBIST path-list into said second scanned circuit path-list based on said constraint file to generate said second LBIST/circuit path-list wherein said circuits in said constraint file are excluded from said insertion into said scanned circuit path-list and said generated second LBIST/circuit path-list.

66. A system in accordance with claim 65, wherein said predetermined sequence of circuit components comprising:

a first circuit component wherein said first circuit component is the first traversed component in said path; and

a second circuit component wherein said second circuit component is the last traversed component in said path.

67. A system in accordance with claim 66, wherein said first traversed component is a scan-enabled electronic flip-flop.

68. A system in accordance with claim 66, wherein said first traversed component is a memory output port.

69. A system in accordance with claim 66, wherein said first traversed component is an external input port.

70. A system in accordance with claim 66, wherein said last traversed component is a scan-enabled electronic flip-flop.

71. A system in accordance with claim 66, wherein said last traversed component is a memory input port.

72. A system in accordance with claim 66, wherein said last traversed component is an external output port.

73. A system in accordance with claim 66,  
wherein said first analyzer subsystem is adapted to perform a functional mode timing violations analysis of said circuit path-list; and,  
wherein said generation of a circuit timing violation analysis output includes generation of a circuit functional mode timing violations output path-list.

74. A system in accordance with claim 73, wherein said second analyzer subsystem further comprises:

a third analyzer subsystem adapted to analyze said first LBIST/circuit path-list for functional mode timing violations and to generate an LBIST/circuit functional mode timing violations output path-list; and

a fourth analyzer subsystem adapted to analyze said first LBIST/circuit path-list for an LBIST mode timing violations and to generate an LBIST/circuit LBIST mode timing violations output path-list,

wherein said generated LBIST/circuit timing violations analysis output includes said functional mode timing violations output path-list and said LBIST mode timing violations output path-list.

75. A system in accordance with claim 74, wherein said comparator subsystem compares said LBIST/circuit functional mode timing violations output path-list with said circuit timing violations analysis output path-list and generates a first comparison output path-list; and

wherein said comparator subsystem identifies in said first comparison output path-list a path with a circuit component causing timing violation, wherein said identification is performed based on said predetermined identification protocols.

76. A system in accordance with claim 74, wherein said comparator subsystem compares said LBIST/circuit LBIST mode timing violations output path-list with said LBIST/circuit functional mode timing violations output path-list, generates a second comparison output path-list; and identifies in said second comparison output path-list a path with a timing violation.

77. A system in accordance with claim 75, wherein said comparator subsystem further comprises:

a separator subsystem adapted to separate each path in said LBIST/circuit functional mode timing violations output path-list exclusive from said circuit timing violations analysis output path-list wherein said first comparison output includes said separated paths.

78. A system in accordance with claim 77, wherein said timing violation is a control point timing violation caused by a control point circuit.

79. A system in accordance with claim 77, wherein said timing violation is an observe point timing violation caused by an observe point circuit.

80. A system in accordance with claim 77, wherein said timing violation is an x-bounding timing violation caused by an x-bounding circuit.

81. A system in accordance with claim 78, said predetermined identification protocols comprising:

a protocol to compare each path in said separated paths in said first comparison output path-list with a predetermined control-point-insertion database to identify said control-point timing violation circuits in said path,

wherein said constraint file includes said identified control-point timing violation circuits in said path.

82. A system in accordance with claim 79, said predetermined identification protocols comprising:

a protocol to compare each path in said separated paths in said first comparison output path-list with a predetermined observe-point-insertion database to identify said observe-point timing violation circuits in said path,

wherein said constraint file includes said identified observe-point timing violation circuits in said path.

83. A system in accordance with claim 80, said predetermined identification protocols comprising:

a protocol to compare each path in said separated paths in said first comparison output path-list with a predetermined x-bounding-insertion database to identify said x-bounding timing violation circuits in said path,

wherein said constraint file includes said identified x-bounding timing violation circuits in said path.

84. A system in accordance with claim 76, wherein said comparator subsystem further comprises:

a separator subsystem adapted to separate each path in said LBIST/circuit LBIST mode timing violations output path-list exclusive from said LBIST/circuit functional mode timing violations output path-list wherein said constraints file includes said separated paths.

85. A system in accordance with claim 84, wherein said timing violation is a multi-cycle-path violation.

86. A system in accordance with claim 84, wherein said timing violation is a false-path violation.

87. A system in accordance with claim 83, wherein said modifier subsystem comprising:  
a suppression subsystem adapted to suppress a capture of said last traversed scan-enabled electronic flip-flop in each said path.

88. A system in accordance with claim 83, further comprising:  
a determination subsystem adapted to determine each path in said first LBIST/circuit path-list whose first traversed circuit component is a first circuit component in said predetermined sequence of circuit components in each said separated path; and  
a suppression subsystem adapted to suppress a capture of a last traversed scan-enabled electronic flip-flop in each of said determined paths.

89. A system in accordance with claim 84, further comprising:  
a suppression subsystem adapted to suppress a capture of a last traversed scan-enabled electronic flip-flop in said separated paths.

90. A system in accordance with claim 89, wherein said suppressed component is a receiving flip-flop.

91. A program storage device readable by a machine, tangibly embodying a program of instructions executable by the machine to perform a method for resolving timing violations introduced by a logic built-in self test (LBIST) sub-circuit formed within an underlying integrated circuit, said method comprising:

analyzing a circuit path-list corresponding to said integrated circuit for timing violations and generating a circuit timing violations analysis output;

generating a first LBIST/circuit path-list based on said circuit path-list and an LBIST path-list corresponding to said LBIST sub-circuit;

analyzing said first LBIST/circuit path-list for timing violations and generating an LBIST/circuit timing violations analysis output;

comparing said LBIST/circuit timing violations analysis output with said circuit timing violations analysis output;

generating an LBIST/circuit constraint file based on said comparing and predetermined protocols; and

generating a second LBIST/circuit path-list based on said circuit path-list, said LBIST path-list and said constraints file wherein said timing violations introduced by said LBIST sub-circuit are resolved in said second LBIST/circuit path-list.